

Search Notes

Application No.

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Examiner

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Applicant(s)

BEIL ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
359	326-332	2/25/2004	JDL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO "WEST" Database searched (search strategy on separate sheet)	2/25/2004	JDL
IEEE Xplore Database searched	2/24/2004	JDL